

**Raman scattering in pure and carbon-doped MgB<sub>2</sub> films**D. A. Tenne,<sup>1,\*</sup> X. X. Xi,<sup>1,2,3</sup> A. V. Pogrebnnyakov,<sup>1,2</sup> and J. M. Redwing<sup>2</sup><sup>1</sup>*Department of Physics, Pennsylvania State University, University Park, Pennsylvania 16802, USA*<sup>2</sup>*Department of Materials Science and Engineering, Pennsylvania State University, University Park, Pennsylvania 16802, USA*<sup>3</sup>*Materials Research Institute, Pennsylvania State University, University Park, Pennsylvania 16802, USA*

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We have studied Raman scattering in MgB<sub>2</sub> thin films grown by hybrid physical-chemical vapor deposition on SiC and Al<sub>2</sub>O<sub>3</sub> substrates. The Cooper-pair-breaking peak corresponding to the larger gap was observed and its position correlates with the value of  $T_c$ , which varies with film strain. The temperature dependence of the  $E_{2g}$  phonon frequency and linewidth was studied. Carbon doping of MgB<sub>2</sub> films suppresses  $T_c$ , and leads to a hardening of the  $E_{2g}$  phonon mode, an increased luminescence background in the spectra, and a stronger contribution of disorder-activated phonons to Raman spectra.

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The 39 K superconductor MgB<sub>2</sub> (Ref. 1) has attracted great interest stimulated by its remarkable superconducting properties and potential for applications. MgB<sub>2</sub> has been demonstrated to be a unique example of a two gap superconductor.<sup>2,3</sup> It is a phonon-mediated superconductor with strong electron-phonon coupling<sup>4-9</sup> and phonon anharmonicity.<sup>2,5,8,10,11</sup> Recently, epitaxial MgB<sub>2</sub> thin films have been produced by a hybrid physical-chemical vapor deposition (HPCVD) technique.<sup>12</sup> The HPCVD films are very clean [residual resistivity as low as 0.26  $\mu\Omega$  cm (Ref. 13)] due to the high purity source of B and the highly-reducing H<sub>2</sub> atmosphere during the deposition. The  $T_c$  of the film varies with film thickness, and a tensile strain in the film can raise  $T_c$  well above the bulk value to 41.8 K.<sup>14</sup> Dirty films can also be made using HPCVD by carbon doping, which suppresses  $T_c$  but dramatically enhances the upper critical field  $H_{c2}$  and vortex pinning.<sup>15</sup>

Raman studies on single crystal<sup>16-20</sup> and polycrystalline MgB<sub>2</sub> (Refs. 21-26) revealed features corresponding to the energy gaps and a phonon modes of  $E_{2g}$  symmetry. The latter is the B-B bond stretching mode playing a major role in the mechanism of superconductivity in MgB<sub>2</sub>.<sup>5,6</sup> However, the correlation between the  $E_{2g}$  phonon frequency and  $T_c$  is not clear so far. Yates *et al.*<sup>27</sup> studied room-temperature Raman spectra of polycrystalline MgB<sub>2</sub> films with different  $T_c$ 's and found that the  $E_{2g}$  mode frequency decreases with decreasing the  $T_c$ . Yates *et al.* associated the reduction of  $T_c$  in their samples with magnesium offstoichiometry and oxygen alloying. They explained the observed reduction of  $T_c$  by the drastic decrease of the electron-phonon coupling constant. The Raman studies of carbon-substituted single MgB<sub>2</sub> crystals<sup>28</sup> and polycrystalline powder samples<sup>29</sup> showed that the  $E_{2g}$  mode hardens with decreasing  $T_c$  caused by carbon substitution. The observed hardening of the  $E_{2g}$  mode was associated with the suppression of electron-phonon coupling by carbon substitution.<sup>28</sup> Recently, Pogrebnnyakov *et al.* demonstrated theoretically and experimentally that the  $T_c$  in epitaxial MgB<sub>2</sub> films deposited by HPCVD increases with biaxial tensile strain, and that this increase is due to the softening of the  $E_{2g}$  phonon mode.<sup>14</sup> First-principles calculations showed that the  $E_{2g}$  phonon frequency decrease leads to the large increase in the  $\sigma$  band electron-phonon coupling strength, which more

than compensates the lowering of the temperature or energy scale governed by the phonon frequency itself. In the present paper we report a Raman study of pure and carbon-doped MgB<sub>2</sub> films grown by HPCVD. It shows that the position of the pair-breaking peak correlates with the value of  $T_c$ , and the carbon doping leads to the hardening of the  $E_{2g}$  phonon mode. Together with the results of Masui *et al.*<sup>28</sup> and our recent result on the tensile strain-induced  $T_c$  increasing by the  $E_{2g}$  phonon mode softening,<sup>14</sup> the present result further confirms a correlation between the  $E_{2g}$  phonon frequency and  $T_c$ .

The MgB<sub>2</sub> films were grown on (0001) 4H-SiC and (0001) sapphire substrates. Details of the HPCVD growth have been described elsewhere.<sup>12</sup> We have shown previously that films on (0001) SiC are *c*-axis oriented and epitaxial with an in-plane alignment of the *a* axis of MgB<sub>2</sub> with that of SiC.<sup>30</sup> Films on (0001) sapphire are also *c*-axis oriented and epitaxial, but the *a* axis of MgB<sub>2</sub> is rotated by 30° in-plane from the *a* axis of sapphire.<sup>12</sup> Carbon doping was achieved by adding carbon-containing precursor metalorganic bis-(methylcyclopentadienyl)magnesium to the H<sub>2</sub> carrier gas during the film growth.<sup>15</sup> The carbon-doped films are *c* axis textured with columnar nanograins and highly resistive amorphous areas at the grain boundaries. Pure MgB<sub>2</sub> films studied have  $T_c$  between 39.7 and 41.8 K, depending on the substrate (SiC or sapphire) and film thickness. The carbon concentration in the doped films is between 8 and 29 atomic percent, causing a decrease of the zero-resistance  $T_c$ , which varies from 38.5 to 28.4 K in these samples. The structural and superconducting properties of carbon-doped films studied here were reported elsewhere.<sup>15</sup>

Raman spectra were recorded using a SPEX Triplemate spectrometer equipped with a liquid-nitrogen-cooled multi-channel coupled-charge-device detector. The 514.5 nm line of an Ar<sup>+</sup> laser was used for excitation, and the laser power density was kept at a low level ( $\approx 30$  W/cm<sup>2</sup>) to avoid heating of the sample. Raman spectra from the films were measured in backscattering geometry both in parallel  $z(x, x)\bar{z}$  and perpendicular  $z(x, y)\bar{z}$  polarization configurations ( $z$  direction is normal to the film plane).

MgB<sub>2</sub> has a hexagonal structure with point group  $P6/mmm(D_{6h})$ . Symmetry analysis<sup>22</sup> yields four zone-center

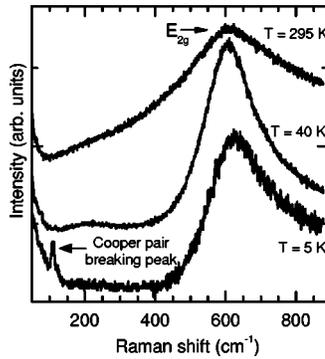


FIG. 1. Raman spectra of a 340-nm-thick MgB<sub>2</sub> film on SiC substrate.

optical phonon modes. Two of them,  $A_{2u}$  and  $B_{1g}$  involve atomic displacements along the  $c$  axis, and two doubly degenerate modes  $E_{1u}$  and  $E_{2g}$  have vibrations only in the  $ab$  plane. Only the  $E_{2g}$  modes are Raman active. According to the results of many studies,<sup>4–9</sup> the  $E_{2g}$  phonons, involving the in-plane vibrations of boron atoms, are strongly coupled to electrons and responsible for superconductivity. Experimentally, a broad, strongly damped phonon mode of  $E_{2g}$  symmetry at 600–630 cm<sup>-1</sup> has been observed. The low-frequency Raman spectra below  $T_c$  contain the features of electronic Raman scattering, corresponding to superconducting gaps.<sup>16–19,21</sup> The larger gap appears as a sharp peak at about 110 cm<sup>-1</sup> (13.6 meV) at 10 K, which is due to the breaking of Cooper pairs by the incident light. Its position corresponds to the double energy of the larger gap  $\Delta_L$ . The smaller gap was observed as a threshold in the low-frequency Raman intensity<sup>18,19</sup> at the energy  $2\Delta_s$  (about 30 cm<sup>-1</sup> at 15 K), caused by the fact that in the superconducting state there are no electronic excitations below the gap.

Figure 1 shows typical Raman spectra of MgB<sub>2</sub> films. In the low-frequency range the spectra below  $T_c$  contain a sharp peak (at 110 cm<sup>-1</sup> at 5 K), which is attributed to the Cooper-pair-breaking peak at the energy  $2\Delta_L$  corresponding to the larger gap ( $\Delta_L(5\text{ K})=6.8\text{ eV}$ ). Low-frequency region of the spectra taken at several temperatures is presented in Fig. 2. (The spectra in Fig. 2 are shown after Raleigh background subtraction.) A similar feature was reported for single crystal<sup>16–19</sup> and polycrystalline samples<sup>21</sup> at about 105 cm<sup>-1</sup>. The higher frequency of the pair-breaking peak in our sample compared to that in the bulk samples is due to the higher  $T_c$  caused by the tensile strain in the film.<sup>13,14</sup> The spectra shown in Figs. 1 and 2 were measured on a 340-nm-thick film on SiC substrate, having the highest  $T_c=41.8\text{ K}$ . For comparison, the 5 K spectrum of a 80-nm-thick film on sapphire, having  $T_c=39.7\text{ K}$  is also shown in Fig. 2 (dotted line). As one can see, in the latter film the Cooper-pair-breaking peak appears at lower frequency compared to the film on SiC. We have shown that thicker films have higher  $T_c$  for both SiC and sapphire substrates, and  $T_c$  is higher on SiC than on sapphire for the same thickness.<sup>13,14</sup> The thinner film on sapphire with lower  $T_c$  shows a smaller gap than thicker film on SiC. The temperature dependence of the gap for all the samples measured is in very good agreement with the prediction of BCS theory. This is illustrated in the inset to

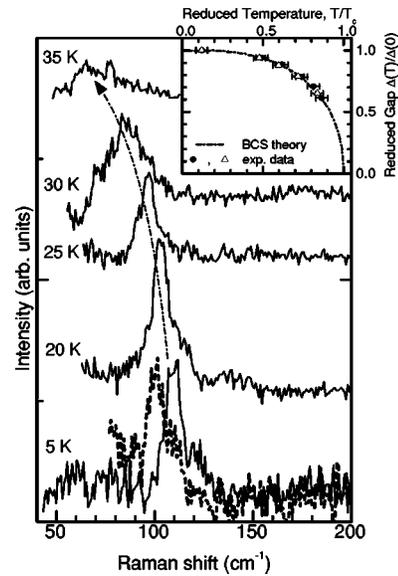


FIG. 2. The Cooper pair breaking peak at different temperatures for a 340-nm-thick MgB<sub>2</sub> film on SiC substrate (solid lines). The peak for 80-nm-thick film on sapphire at 5 K is shown for comparison (dotted line). Inset: temperature dependence of reduced gap for these films on SiC and sapphire substrates (circles and triangles, respectively). Dashed-dotted line shows the prediction of BCS theory.

Fig. 2, showing the reduced gap  $\Delta_L(T)/\Delta_L(T_0)$  as a function of the reduced temperature  $T/T_c$ , where  $\Delta_L(t_0)$  is the gap value at  $T=0$  for two samples. The second, smaller gap should appear as a threshold in Raman intensity at about 30 cm<sup>-1</sup>. We were not able to observe this feature because of the strong background of elastically scattered light.

The higher frequency part of the Raman spectra shown in Fig. 1 is dominated by the broad feature of the  $E_{2g}$  phonon, centered at about 615 cm<sup>-1</sup>. The temperature dependence of the  $E_{2g}$  phonon peak position and linewidth for the 340 nm-thick MgB<sub>2</sub> film on SiC substrate is presented in Fig. 3. As can be seen from the figure, the phonon frequency shows almost no dependence on temperature over the entire temperature range 5–300 K, (the observed frequency shift between 5 and 300 K is about 10 cm<sup>-1</sup>, which is within the experimental uncertainties) and does not undergo any notice-

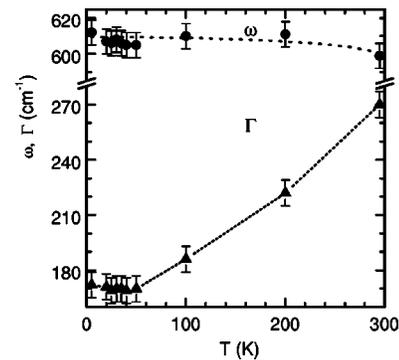


FIG. 3. Temperature dependence of the  $E_{2g}$  phonon frequency (circles) and linewidth (triangles) for MgB<sub>2</sub> film on SiC substrate.

able changes upon transition from normal to superconducting state predicted by density-functional calculations.<sup>5</sup> The  $E_{2g}$  mode is characterized by extremely large linewidth ( $\sim 170$   $\text{cm}^{-1}$  at 5 K), similar to the observations of other authors on single crystal and polycrystalline  $\text{MgB}_2$ .<sup>16,23–26</sup> The linewidth remains nearly constant in the temperature range 5–50 K, and shows no change at  $T_c$ . Further temperature increase leads to gradual increase of the linewidth up to  $\sim 270$   $\text{cm}^{-1}$  at room temperature. Similar temperature behavior of the  $E_{2g}$  phonon frequency and linewidth was observed for other samples studied here, and was also reported for bulk  $\text{MgB}_2$ .<sup>25,26</sup>

The phonon line broadening with increasing temperature may arise from the anharmonic decay of the  $E_{2g}$  mode into two other phonons, as strong anharmonicity of this mode has been predicted.<sup>5,8</sup> However, the phonon anharmonicity cannot explain the linewidth of  $170$   $\text{cm}^{-1}$  at 5 K. The large  $E_{2g}$  phonon linewidth may be due to the strong electron-phonon interaction, causing the phonon decay into electron-hole pairs. A recent study by inelastic x-ray scattering<sup>10</sup> and calculations using density functional theory<sup>10,11</sup> showed that the contribution of phonon anharmonicity to the  $E_{2g}$  mode broadening is small and the dominant contribution to the linewidth is the electron-phonon coupling. The latter can also give rise to the increase of the linewidth with temperature,<sup>25</sup> similar to the experimentally observed behavior shown in Fig. 3.

Figure 4 shows a Raman spectrum of a carbon-doped  $\text{MgB}_2$  film on SiC substrate (carbon concentration is 26 atomic percent, and zero-resistance  $T_c$  is 32.5 K) in comparison with a pure film (the latter is the same as shown in Fig. 1). Carbon doping strongly affects the Raman spectrum of the film, which is characterized by significantly higher background likely due to the luminescence from impurity phases.<sup>25</sup> The spectrum of the undoped film has a very low background because of the high purity of the film.<sup>13</sup> The  $E_{2g}$  peak of the pure film has a slightly asymmetric lineshape with a shoulder at the high frequency side due to the maximum in the phonon density of states at about  $780$   $\text{cm}^{-1}$  (Refs. 8, 9, and 31). The phonon density-of-states peak becomes significantly stronger in carbon-doped films. (See the inset to Fig. 4, showing the fitting of the spectra after the linear background subtraction. As the luminescence peak is much broader than the whole range of the Raman spectra,<sup>25</sup> the linear approximation for the luminescence background, shown by thin dashed-dotted line on Fig. 4, is appropriate here.) This is due to increased disorder induced by carbon doping. Similar increase in the phonon density-of-states peaks was also observed in  $\text{MgB}_2$  films after Ar ion bombardment.<sup>32</sup> Figure 4 clearly shows that the  $E_{2g}$  phonon line shifts substantially to a higher frequency upon carbon

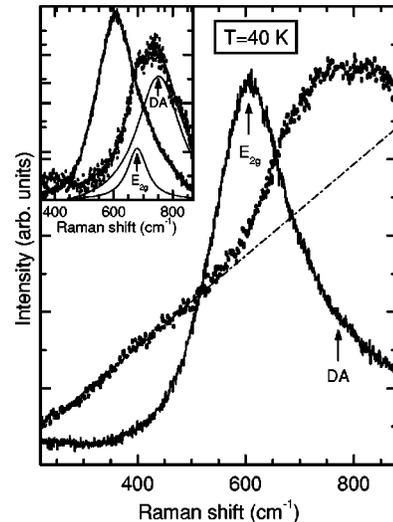


FIG. 4. Raman spectra of pure (black solid line) and carbon doped (grey dotted line)  $\text{MgB}_2$  films on SiC substrate, measured at  $T=40$  K. Inset shows the spectra after the linear background subtraction. Thin black lines show the result of fitting.

doping, from  $605$  to about  $680$   $\text{cm}^{-1}$ . There have been previous reports that a reduced  $T_c$  in  $\text{MgB}_2$  corresponds to a higher  $E_{2g}$  phonon frequency.<sup>24,28</sup> Our result confirms this correlation.

In summary, Raman spectroscopy was applied to study both pure and carbon-doped  $\text{MgB}_2$  thin films grown by HPCVD. The pair-breaking peak corresponding to the larger superconducting gap was found to correlate with the value of  $T_c$  for different films, which is substrate- and thickness-dependent due to different strain state of the films. The frequency of the  $E_{2g}$  phonon mode in films increases with carbon substitution, which corresponds to the reduced  $T_c$ . This is in agreement with the recent results of Masui *et al.*<sup>28</sup> In our recent study we have demonstrated by first-principles calculations confirmed by experimental results, that a tensile strain-induced  $E_{2g}$  mode softening causes  $T_c$  to increase above the bulk value.<sup>15</sup> In combination with the results presented here that the carbon doping causes the  $E_{2g}$  mode hardening and reduces  $T_c$ , we believe that a correlation between the  $E_{2g}$  phonon frequency and  $T_c$  of  $\text{MgB}_2$  can be established.

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